

Soft X-ray Microscopy Project at NSRL

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The Hefei Synchrotron Radiation Facility, a national synchrotron radiation source was operated and available for experiments at the end of 1991. This 800 MeV storage ring produces the synchrotron radiation in the spectral range from infrared to VUV and soft x-ray microscopy has been planned at Hefei National Synchrotron Radiation Laboratory (NSRL) since 1984 (Xie et al.) The aims of our soft x-ray microscopy project are the construction of a soft x-ray scanning microscope, development of soft x-ray scanning microscope, development of soft x-ray scanning microscope, development of soft x-ray contact imaging techniques and demonstration of the unique capabilities of soft x-ray microscopy in high resolution, element-specific studies of biological specimens. We also begin the project of other types soft x-ray imaging study, e.g. x-ray holography.

A Prototype scanning transmission x-ray microscope has been installed in beamline U12A. In the first generation of our instrument the x-ray probe is formed by a 2 μ m pinhole. We have tested this scanning x-ray microscope and obtained the real time x-ray image using synchrotron radiation. The specimen on stage is mechanically scanned across the x-ray spot. The continuous scan (50 μ m \times 50 μ m) is generated by a pair of PZTs and the fast scan direction is horizontal. The PZTs are driven by fast, high voltage (1000) operational amplifiers which are controlled by low voltage signals from a CAMAC DAC. The position is sensed by a pair of LVDTs, the output of which is converted to a voltage by a high gain signal processor and inputted to two channels of a CAMAC ADC. The x-rays transmitted by specimen are detected by a flow gas proportional counter which is fabricated in our lab. The x-ray micrograph is displayed on a color monitor via the video display interface and

can be stored on a hard disk or diskette. Simple image processing can be done in these stored images including changing contrast and color level, pixel size and starting position (Xie et al.). The effort of constructing a new x-ray scanning microscope is undertaken. In the next generation of the instrument a high resolution micro zoneplate with outermost zone width 45 nm which was fabricated at IBM (Anderson et al.) will be used to focus the x-rays. An improved scanning stage and an x-ray image processing system also will be made.

Studies of soft x-ray contact microscopy have been performed using synchrotron radiation. We designed and built a prototype device for doing the specimen exposure with synchrotron radiation. This device is vacuum compatible and convenient for the specimen handling. Typical time to reach pressure of the order of 10⁻⁵ torr is about 10 minutes. The specimen holder consists of five holes in which one is painted on P-31 phosphor for beam alignment and others hold specimen-resist assembly. The holder can be moved to exact position through a linear feedthrough. We also developed and tested a wet specimen chamber. A Si₃N₄ window of thickness 1000 Å is used to separate the beamline vacuum and the exposure area. The Si₃N₄ windows which is fabricated in our laboratory has been used without breaking and leaking. Exposures in a broad-band beam and monochromatic beam have been made. Simple grid and some biological specimens have been chosen for examination and demonstration (Jia et al.).

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